IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of

Makoto AKIZUKI et al.

Serial No. NEW : Attn: APPLICATION BRANCH

Filed August 27, 2003 : Attorney Docket No. 2003-1240

METHOD FOR FORMING GAS CLUSTER AND METHOD FOR FORMING THIN FILM (Rule 1.53(b) Continuation of Serial No. 10/025,899, Filed December 26, 2001)

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Sir:

Pursuant to the provisions of 37 CFR 1.56, 1.97 and 1.98, Applicants request consideration of [X] the references listed on attached form PTO-1449 and/or [] the additional information identified below in paragraph 3. A legible copy of each reference listed on the form PTO-1449 and each U.S. patent application listed below is enclosed, except a copy is not provided for each reference previously cited by or submitted to the Patent Office in prior parent application Serial No. 10/025,899.

1a. [X] This Information Disclosure Statement is submitted:

within three months of the filing date (or of entry into the National Stage) of the above-entitled application, or

before the mailing of a first Office Action on the merits or the mailing of a first Office Action after the filing of an RCE,

and thus no certification and/or fee is required.

lb.	n	This	Informati	on D	isclosure	Statement	is	submitted
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after the events of above paragraph 1a and prior to the mailing date of a final Office Action or a Notice of Allowance or an action which otherwise closes prosecution in the application, and thus:

- (1) [] the certification of paragraph 2 below is provided, or
- (2) [] the fee of \$180.00 specified in 37 CFR 1.17(p) is enclosed.
- 1c. [] This Information Disclosure Statement is submitted:

after the mailing date of a final Office Action or Notice of Allowance or action which otherwise closes prosecution in the application, and prior to payment of the issue fee, and thus:

the certification of paragraph 2 below is provided, and

the fee of \$180.00 specified in 37 CFR 1.17(p) is enclosed.

2. It is hereby certified

- a. [] that each item of information contained in this Information Disclosure Statement was first cited in any communication from a foreign patent office in a counterpart foreign application not more than three months prior to the filing of the Statement, or
- b. [] that no item of information contained in the Information Disclosure Statement was cited in a communication from a foreign patent office in a counterpart foreign application and, to the knowledge of the person signing the certification after making reasonable inquiry, was known to any individual designated in §1.56(c) more than three months prior to the filing of the Statement.
- 3. [] Consideration of the following list of additional information (including any copending or abandoned U.S. application, prior uses and/or sales, etc.) is requested.

4.		r each nade t	non-English language reference listed on the attached form PTO-1449, reference to:								
	a.	[]	a full or partial English language translation submitted herewith,								
	b.	[]	a foreign patent office search report (in the English language) submitted herewith,								
	c.	[]	the concise explanation contained in the specification of the present application at page ,								
	d.	[]	the concise explanation set forth in the attached English language abstract,								
	e.	[]	the concise explanation set forth below or on a separate sheet attached to the reference:								
5.	[]	A for	eign patent office search report citing one or more of the references is enclosed.								
			Respectfully submitted,								
			Makoto AKIZUKI et al.								
			Matthew Jacob Registration No. 25,154 Attorney for Applicants								
MJ/krl Washington, D.C. 20006-1021 Telephone (202) 721-8200 Facsimile (202) 721-8250 August 27, 2003			721-8200 721-8250 THF COMMUNICATION								

Sheet 1 of 2					<u> </u>					
FORM PTO 1449 (n		ATTY DOCKET NO. SERIAL N 2003-1240 NEW			NO.					
U.S. PATI LIST OF	APPLICANT Makoto AKIZUKI et al.									
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*EXAMINER INITIAL		DOCUMENT NUMBER	DATE		NAME	1 1		FILING D		
	АА	5,459,326	10/1995	Ya	amada					
	АВ	5,110,435	5/1992	Hal	berland					
	AC	5,350,607	9/1994	Tys	on et al.					
	AD 4,624,859 11/1986 Akira et al.									
	AE 4,066,527 1/1978 Takagi et al.				ļ	· · · · · · · · · · · · · · · · · ·				
	AF	4,882,023	2,023 11/1989 Wendman							
	AG	4,812,326	3/1989	Tsuka	zaki et al.					
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FOREIGN PATENT DOCUMENTS										
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		OTHER C	OCUMENT(S) (In	cluding Author	, Title, Date, Pertii	nent Pag	es, Etc.)			
	AJ "NEW HORIZONS IN MATERIALS PROCESSING WITH ICB", Isao Yamada, Proc. 14th Symp. on ISIAT '91, Tokyo, (1991), Ion Beam Engineering Experimental Laboratory, pp. 227-235.									
	AK	"IRRADIATION EFFECTS OF A MASS ANALYZED GAS CLUSTER ION BEAM ON SILICON SUBSTRATES", Y. Yamashita et al., Proc. 1st Meeting on IESI '92, Tokyo, Ion Beam Engineering Experimental Laboratory, pp. 247,250.								
	AL	"Irradiation effects of gas-cluster Co ₂ ion beams on Si", I. Yamada et al., Nuclear Instruments and Methods in Physics Research B74 (1993) pp. 341-346.								
	АМ	"Surface modification with gas cluster ion beams", I. Yamada et al., Nuclear instruments and Methods in Physics Research B79 (1993) pp. 223-226.								
	AN	"A Method and apparatus for surface modification by gas-cluster ion impact", J.A. Northby et al., Nuclear Instruments and Methods in Physics Research B79 (1993) pp. 336-340.								
	AO	"Cluster Formation Gas", Hagena et al								
EXAMINER	EXAMINER DATE CONSIDERED						-			

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Sheet 2 of 2											
FORM PTO 1449 (modified) U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE LIST OF REFERENCES CITED BY APPLICANT(S)				1 1			ERIAL NO. IEW				
				APPLICANT Makoto AKIZUKI et al.							
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U.S. PATENT DOCUMENTS											
*EXAMINER INITIAL		DOCUMENT NUMBER				SUBCLASS	FILING DA				
	АА	5,091,009	12/1989	Nogami et al.							
	АВ	5,561,326	1/1993	Ito et al.							
	AC	5,527,731	6/1996	Yamamoto et al.							
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			FORE	EIGN PATENT DOCUMENTS	Υ						
		DOCUMENT NUMBER	DATE	COUNTRY	C	LASS	SUBCLASS	TRANSLATION YES NO			
	AJ	4-354865	12/1992	Japan				Х			
	AK	5-102083	4/1993	Japan		<u></u>		Х			
	AL	60-14440	1/1985	Japan				х			
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	AN	6-224146	8/1994	Japan					Х		
	1	OTHER (OCUMENT(S) (Inc	cluding Author, Title, Date, Pertir	nent Pag	es, Etc.)	······································				
	AO	"Micromachining with cluster ions", Henkes et al., Vacuum/volume 39, no. 6, pp. 541-542, 1989.									
42	АР								-		
	AQ				-						
EXAMINER		"Cluster Formation in Expanding Supersonic Jets: Effect of Pressure, Temperature, Nozzle Size, and Test Gas", Hagena et al., The									

^{*}EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.